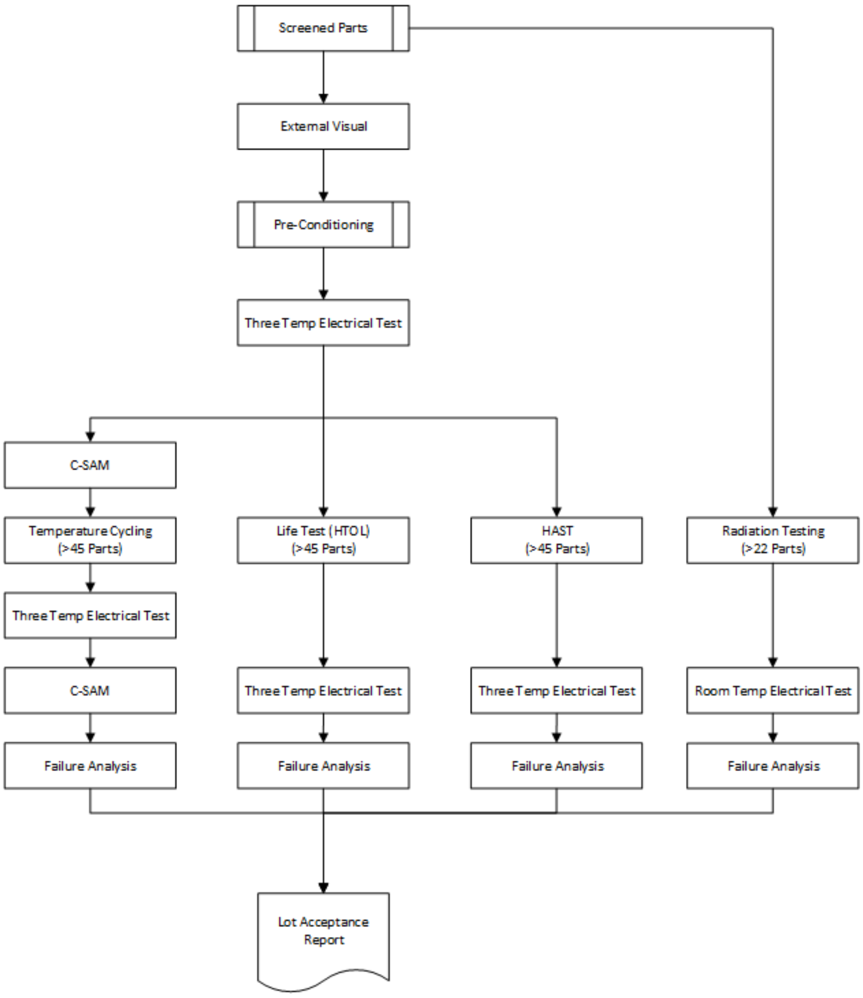
1. Type of Change (Major or Minor)

Major

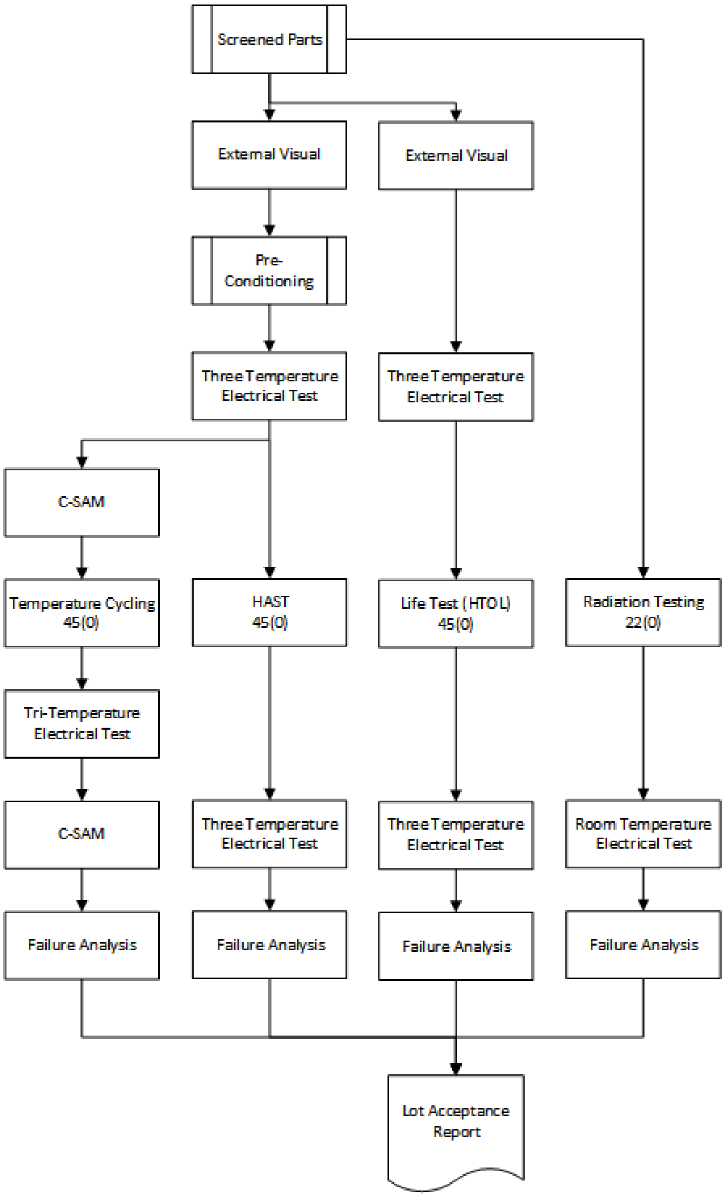
2. Change Description

Preconditioning is being removed from Apogee Semiconductor's HTOL lot acceptance flow to better align with industry standards (MIL-PRF-38535 and JESD47). Preconditioning will still be conducted prior to temperature cycling and HAST stress tests.

Changed From:



Changed to:



3. Impact on Product and/or Process

Simplified lot acceptance flow for the HTOL stress.

4. Justification for Change

Pre-conditioning is not required prior to the 1,000 hour HTOL test according to MIL-PRF-38535 group C requirements nor JESD47 HTOL requirements. Pre-conditioning is primarily a package stress while HTOL is primarily a silicon stress.

5. Change Risk Assessment

Low. This change is in line with industry standards and preconditioning will still be completed prior to temperature cycling and HAST stress testing.

6. Qualification Plan

N/A

7. Qualification Report

N/A

8. Summary

See change description

9. Impacted Device - Document - Process List

All A-grade, B-grade, and C-grade devices

10. Sample Availability Date and Projected Production Shipment

Sample availability date: N/A.

Projected production shipment date: February 28, 2025 or upon PCN approval.

11. File Attachment

Existing lot acceptance flow: Apogee_Lot_Acceptance_Flow_A03.pdf

Updated lot acceptance flow: Apogee_Lot_Acceptance_Flow_A04.pdf